

Extreme High Vacuum System of High Brightness Electron Source for ERL



Tuesday, September 6, 2011
IPAC2011, San Sebastian, Spain

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Outline

- Background
- Overview of the vacuum system for a 500 kV electron gun
- Total outgassing rate measurement
- Pumping speed measurement in UHV
- Summary

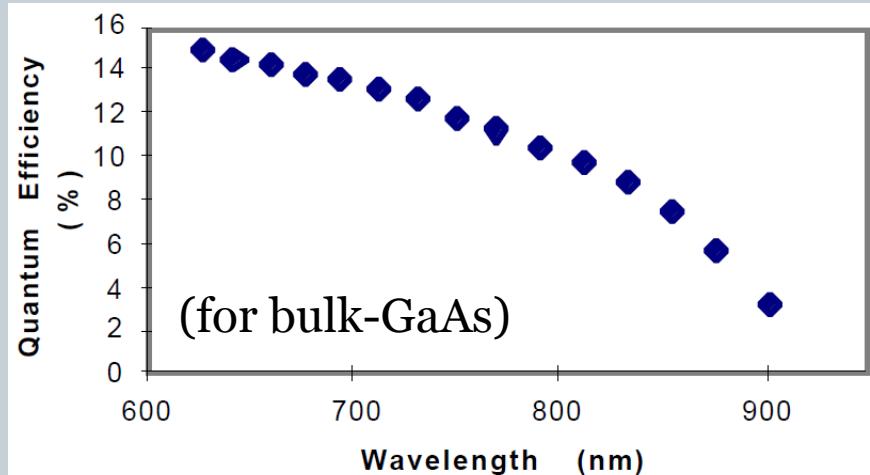


Simple formula of ultimate pressure

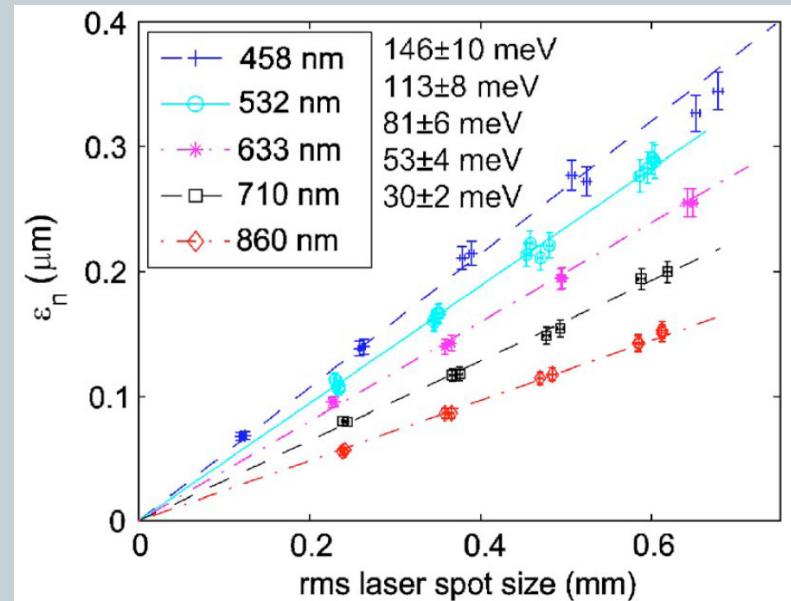
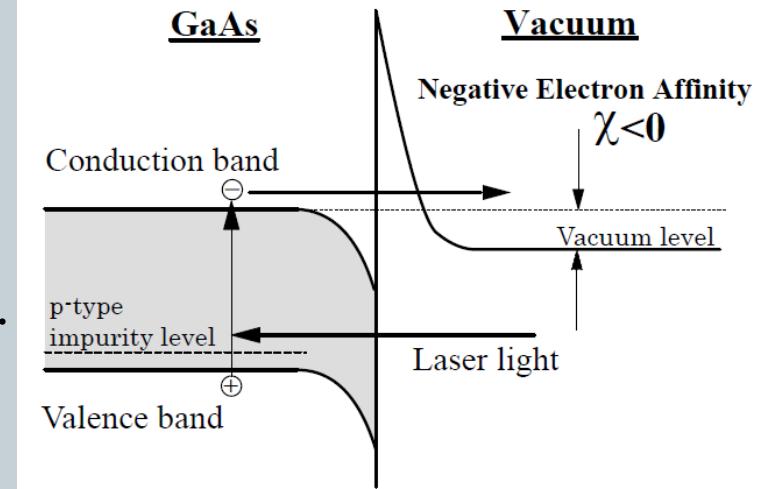
$$P \text{ [Pa]} = \frac{Q \text{ [Pa} \cdot \text{m}^3/\text{s}]}{S \text{ [m}^3/\text{s]}}$$

Background (1)

- GaAs-based high brightness DC-gun
 - A GaAs photocathode with negative electron affinity (NEA) surface can produce low emittance electron beams.
 - High quantum efficiency of > 10 % can be achieved.



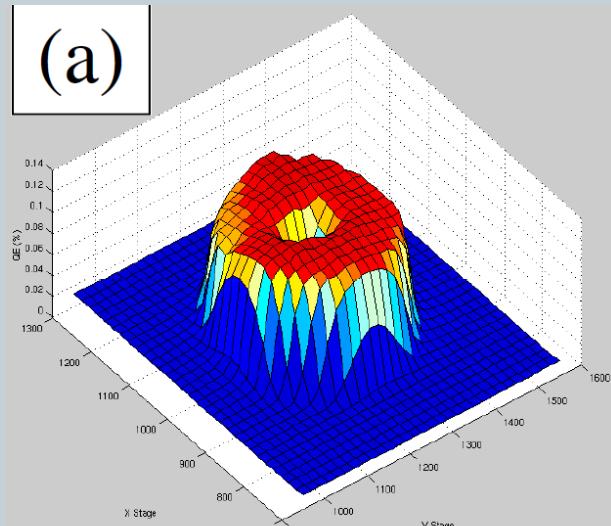
Reference: C. K. Sinclair et al., Proceedings of PAC97 p.2864



Reference: I. V. Bazarov et al., J. Appl. Phys. 103, (2008) 054901

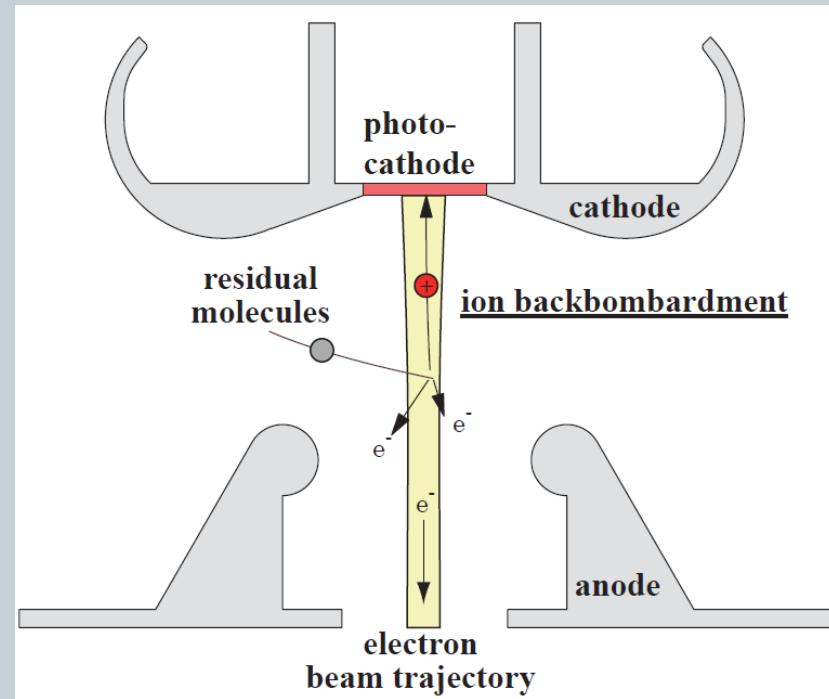
Background (2)

- Cathode lifetime problem
NEA surface is easily degrade by ion back-bombardment.



Reference: C. K. Sinclair et al., Phys. Rev. STAB 10, (2007) 023501

Charge lifetime is limited ~1000 Coulomb for 10 mA operation under the pressure range of $\sim 10^{-9}$ Pa.



Lifetime τ is defined as

$$QE(t) = QE_0 \cdot e^{-\frac{t}{\tau}}$$

Charge lifetime Q_τ is defined as

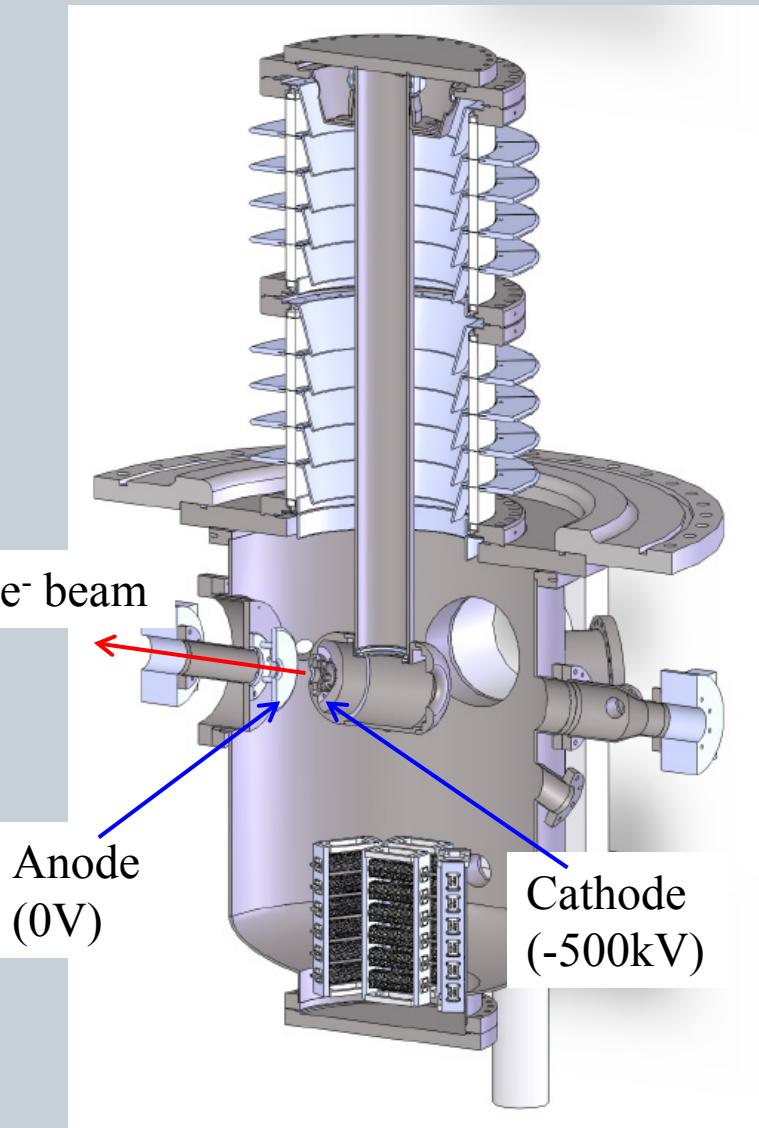
$$Q_\tau = \int_0^\tau I_{beam}(t) dt$$

Overview of electron source vacuum system

- High voltage insulator
 - Inner diameter of $\phi=360$ mm
 - Segmented structure
- Low outgassing material
 - Large titanium vacuum chamber ($ID \sim \phi 630$ mm)
 - Titanium electrode, guard rings
- Main vacuum pump system
 - Bakeable cryopump
 - NEG pump ($> 1 \times 10^4$ L/s, for hydrogen)
- Large rough pumping system
 - 1000 L/s TMP & ICF253 Gate valve

Goal

Ultimate pressure : 1×10^{-10} Pa



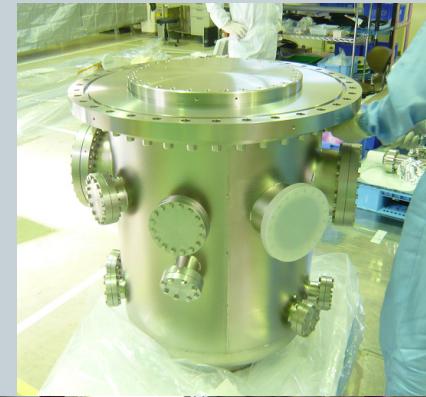
Total outgassing rate measurement (1)

- Method : Rate-of-Rise (RoR) measurement

$$\frac{dP}{dt} = \frac{Q \text{ [Pa} \cdot \text{m}^3/\text{s}]}{V \text{ [m}^3]}$$

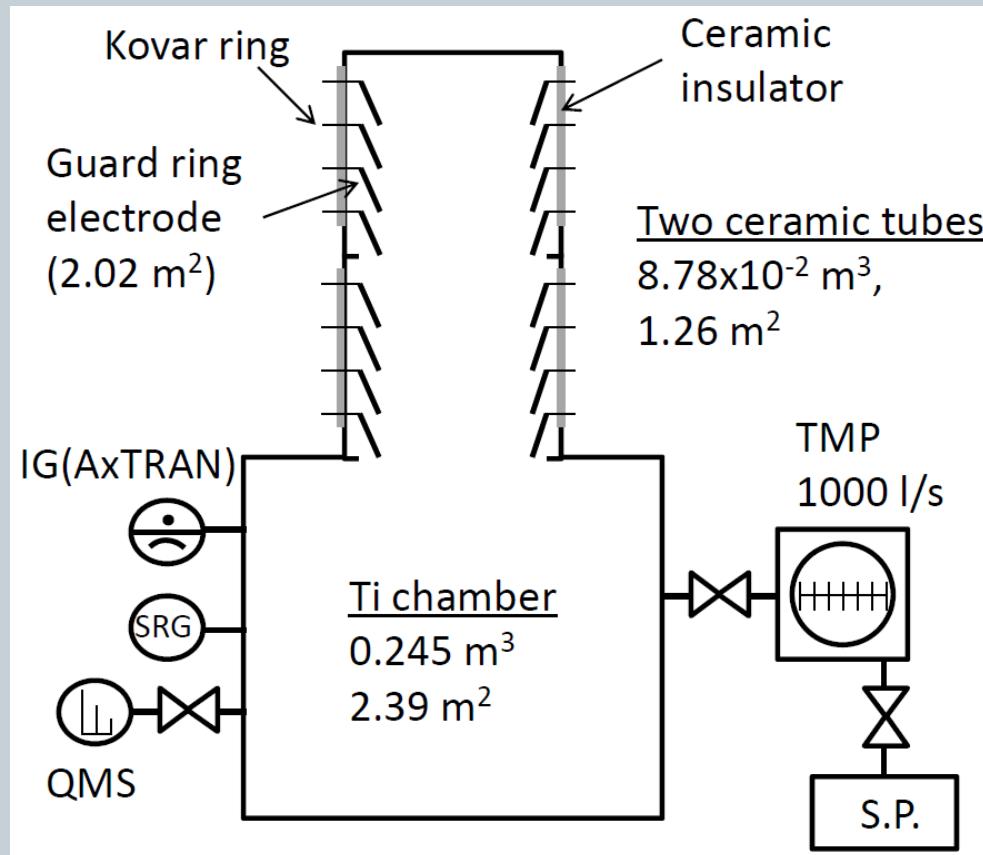
Q: total outgassing rate
V: chamber volume

- Process of measurements
 - Individual bakeout & RoR measurement.
 - Titanium chamber (150 °C, 50 hrs)
 - Ceramic insulator tubes (200 °C, 100 hrs)
 - Assembled each part and guard ring electrodes.
 - Bakeout & measurement of the total system.



Total outgassing rate measurement (2)

- Assembled dc gun system



Spinning rotor gauge (SRG) was employed to suppress outgassing from the gauge.

Total outgassing rate measurement (3)

- Result of assembled RoR measurement (measured by SRG)

Baking condition

temperature: 150~200 °C

period: 100 hours

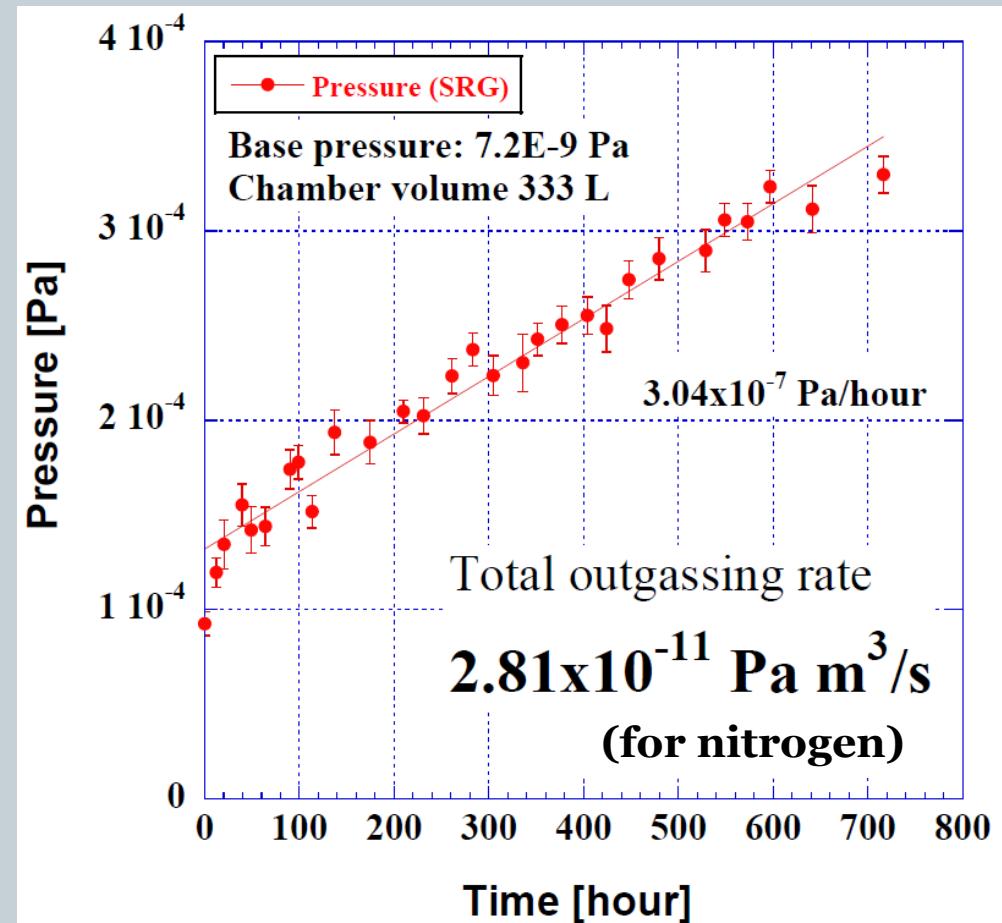
Compensation factor for SRG

$$P_{H_2} = \sqrt{\frac{M_{N_2}}{M_{H_2}}} \cdot P_{N_2}$$

Total outgassing rate

$$Q = 1.05 \times 10^{-10} \text{ Pa m}^3/\text{s}$$

(for hydrogen)



Estimation of total outgassing rate from all system

Installed components	Surface area A [m ²]	Total outgassing Q [Pa·m ³ /s] (SRG)
Gun chamber body	2.4	1.1x10⁻¹⁰ (w/o viewports)
Ceramic insulator tubes	1.6	
Guard ring electrodes	2	
Gate valves & View ports	~0.3	
Installation scheduled components		estimated total outgassing Q [Pa·m ³ /s]
Cathode electrode & Support rod	~1.5	(≤1.5x10 ⁻¹⁰)
Anode electrode	<0.3	(~3.0x10 ⁻¹¹)
NEG cartridges support	<0.5	(≤2.5x10 ⁻¹¹)
Cryopump chamber	<0.5	(≤2.5x10 ⁻¹¹)
Total Q of the DC-gun		Goal : < 3x10⁻¹⁰

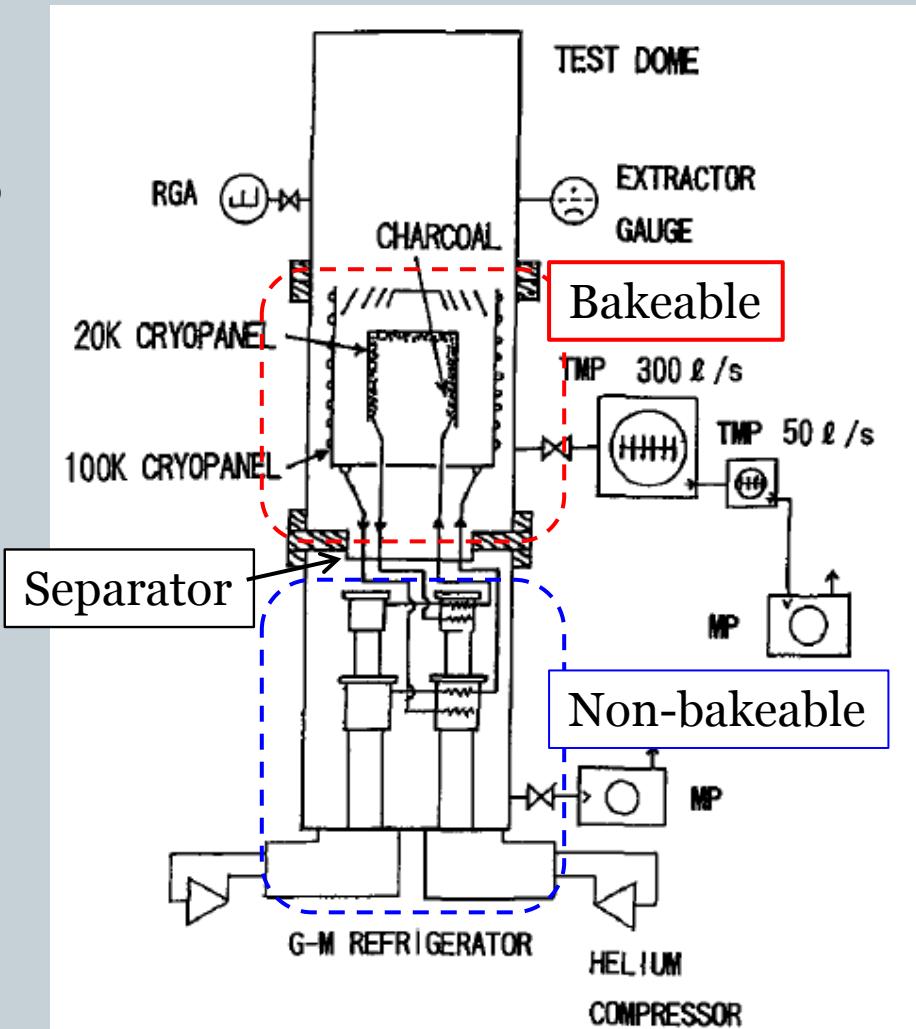
(The values of the total outgassing rate are equivalent for hydrogen.)

Bakeable Cryopump

- Features of the structure
 - G-M refrigerator system is separated spatially from cryopump housing.
 - Adsorbent is fixed on a cryopanel without resin.

Cryopump housing has a capability for baking over 150 °C including adsorbent. (high temperature regeneration of adsorbent is possible.)

Bakeable cryopump can achieve high performance for cryo-sorption under UHV condition.



Reference: H. Yamakawa, Vacuum 44, (1993) 675

Pumping speed measurement

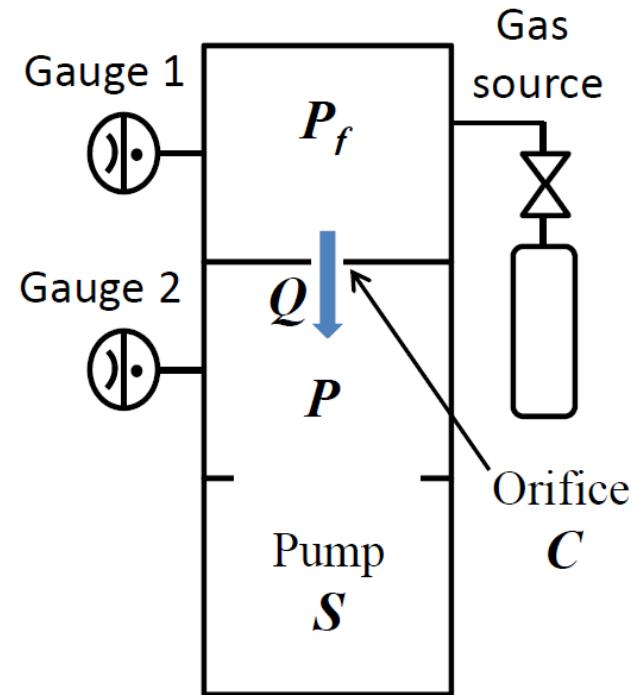
- Principle

$$S \text{ [m}^3/\text{s}] = \frac{Q \text{ [Pa} \cdot \text{m}^3/\text{s}]}{P \text{ [Pa]}}$$

Basically, pumping speed (S) depend on the pressure (P) and gas species.

- Key issues

- Precise measurement for pressure (P) and gas flow (Q)
- Q is decided by conductance (C) and differential pressure ($\Delta P = P_f - P$) between pump test chamber and gas introduction system.



$$\begin{aligned} Q \text{ [Pa m}^3/\text{s}] &= \Delta P \text{ [Pa]} \cdot C \text{ [m}^3/\text{s]} \\ &= (P_f - P) \cdot C \end{aligned}$$

Standard conductance element

- Special features

- The element was made of sintered stainless steel with a pore size of less than 1 μm .
- Molecular flow is realized at a pressure of $< 10^4 \text{ Pa}$.

- Gas flow Q [$\text{Pa m}^3/\text{s}$]

$$Q [\text{Pa} \cdot \text{m}^3/\text{s}] = P_f [\text{Pa}] \cdot C [\text{m}^3/\text{s}] \cdot \sqrt{\frac{28}{M_a}} \sqrt{\frac{T [\text{K}]}{T_0}}$$

$(P_f >> P)$



In this experiment, $C=3.03\times 10^{-10} [\text{m}^3/\text{s}]$ ($T_0=T=300\text{K}$, for nitrogen)

- Advantages

- Conductance is easily compensated for gas species by the molecular mass.
- Conductance is constant against changing in the upstream pressure of $< 10^4 \text{ Pa}$.
- Dependence of flow rate on the temperature is small in RT.

The calibrated element is commercially available from AIST.

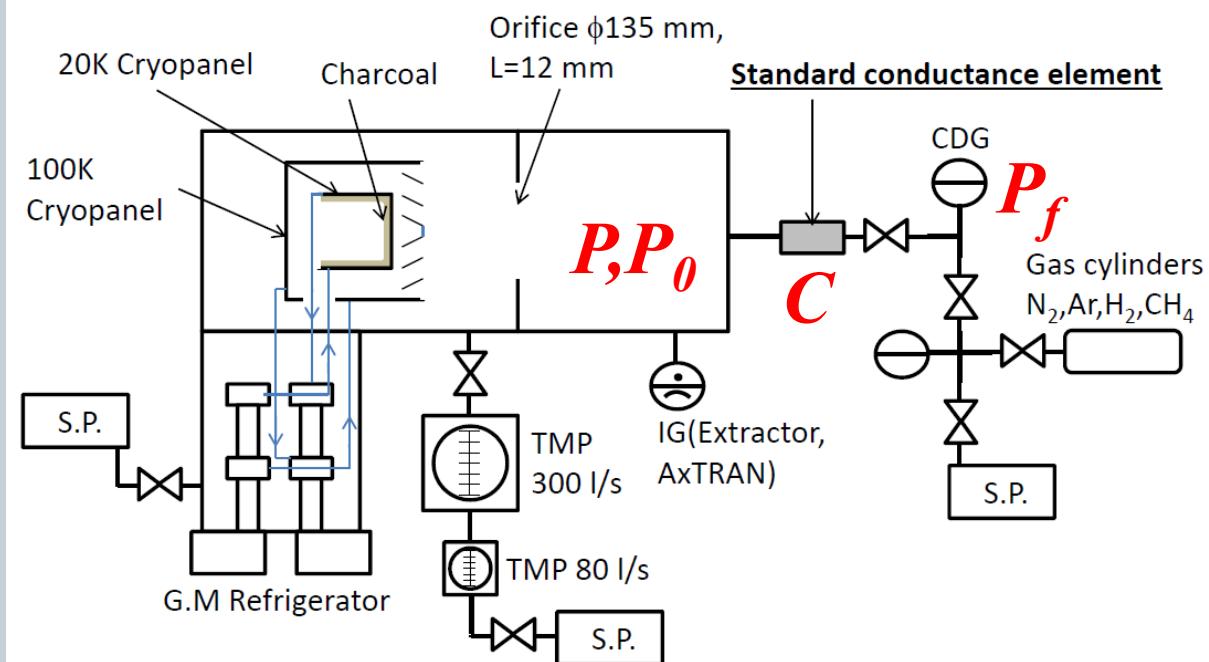
Pumping speed measurement system

Pumping speed

$$S_{(P)} = \frac{Q(P_f)}{(P - P_0)/\alpha}$$

Relative sensitivity factor: α

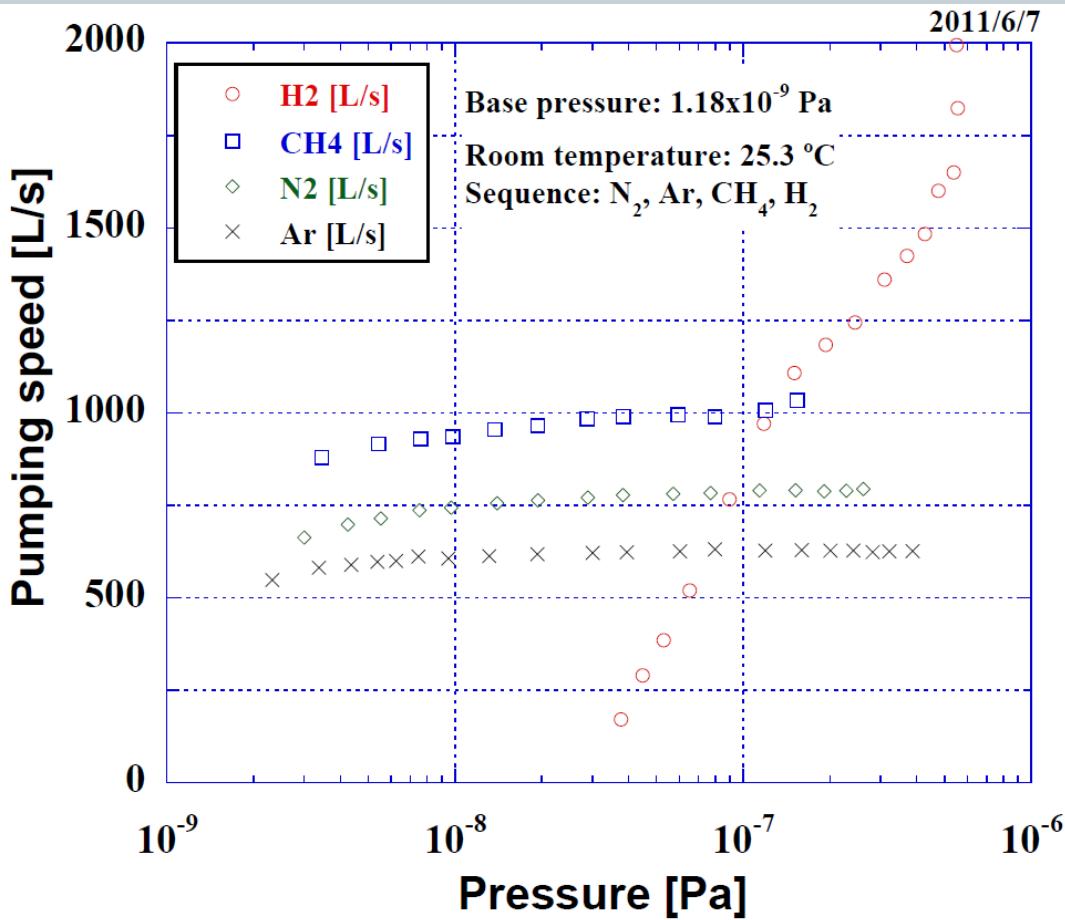
	ATG	EXG
H ₂	0.48	0.45
CH ₄	1.69	1.56
Ar	1.43	1.41



$$Q [\text{Pa} \cdot \text{m}^3/\text{s}] = P_f [\text{Pa}] \cdot C [\text{m}^3/\text{s}] \cdot \sqrt{\frac{28}{M_a}} \sqrt{\frac{T [\text{K}]}{T_0}}$$

- Pressure measurement (P, P_0)
 - Axial Transmission Gauge (ATG)
 - Extractor Gauge (EXG)
- Gas flow control (Q)
 - Standard conductance element (C)
 - Capacitance Diaphragm Gauge (P_f)

Pumping speed of 20 K bakeable cryopump



Baking condition

temperature: 200~230 °C
period: 80 hours

Base pressure: 1.2×10^{-9} Pa

The result was calculated from the pressure data of ATG.

The result was almost the same tendency by using the data of EXG.

Pumping probability

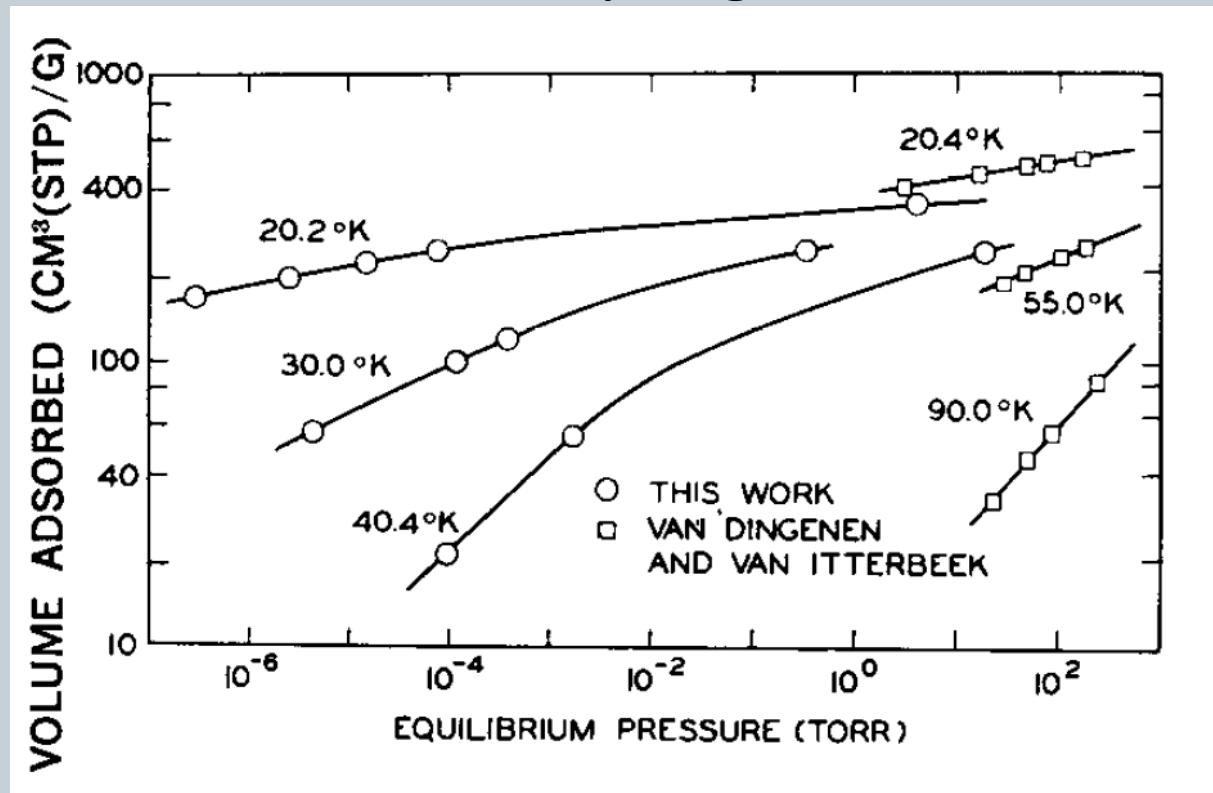
$$\frac{N_p}{N_0} \sim 0.5$$

For N₂, CH₄, Ar

Cryo-condensation or cryo-sorption is functioned well for N₂, CH₄ and Ar. However, cryo-sorption is limited for H₂ under the pressure of $< 10^{-6}$ Pa.

Adsorption Equilibrium

- Adsorption equilibrium of charcoal for hydrogen

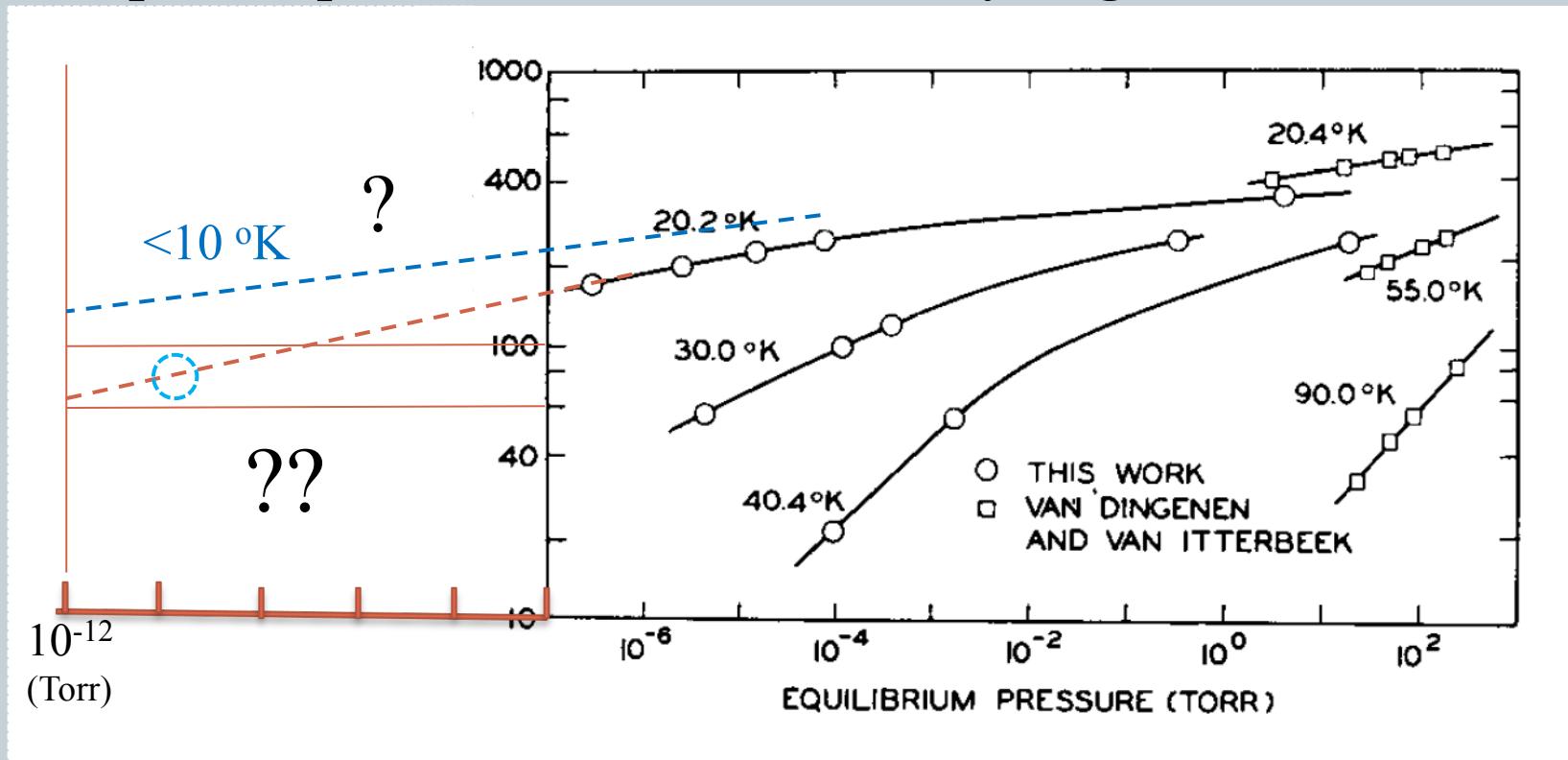


Ref. S. A. Stern, et al., J. Vac. Sci. Technol. 2, (1965) 165.

Cryo-sorption for hydrogen on a charcoal depends on the temperature of charcoal and the concentration of hydrogen in the charcoal.

Adsorption Equilibrium

- Adsorption equilibrium of charcoal for hydrogen



Ref. S. A. Stern, et al., J. Vac. Sci. Technol. 2, (1965) 165.

Cryo-sorption for hydrogen on a charcoal depends on the temperature of charcoal and the concentration of hydrogen in the charcoal.

Degassing by a long term baking or operation at low temperature is necessary.

Summary & Future

- The total outgassing rate of the dc gun with main components was suppressed to $Q \sim 1 \times 10^{-10}$ [Pa m³/s].
 - Outgassing from the remaining components should be suppressed.
- The pumping speed of the 20 K bakeable cryopump was obtained for nitrogen, methane, argon, and hydrogen.
 - The ultimate pressure of the bakeable cryopump was limited by adsorption equilibrium of adsorbent for hydrogen.
 - A test about 4 K bakeable cryopump is in progress.

The possibility of generating extreme high vacuum of 1×10^{-10} Pa in the actual dc gun is still remained !